

ABSTRACT

The present invention relates to a system for
5 testing the connection paths of a switch fabric by using
a spontaneously emitted signal as a test signal. The
system includes at least one first module and at least
one second module, wherein each one of the second modules
is associated to one of the first modules through a
10 connection path in the switch fabric. Each of the first
modules is capable of obtaining a respective first
measurement of a characteristic of the spontaneously
emitted signal supplied to the switch fabric, and each of
the second modules is capable of obtaining a respective
15 second measurement of the characteristic of the
spontaneously emitted signal. The system further includes
a processing module in communication with each of the
first and second modules for determining a feature of the
optical component based on the first and second
20 measurements.